



## Lifetime test for height-level sensors

### Product description

This system enables the automatic life testing of up to seven height-level sensors. For easy handling, the specimen holders are located in the test fixture next to the arranged one another. All actuating and drive elements are also included in the protective housing. In the associated climatic chamber, ambient temperatures of  $-40^{\circ}\text{C}$  to  $+120^{\circ}\text{C}$  can be simulated. The extensive measuring and testing technology is used in a separate rack.

### Field of application

Research & Development, life time testing and quality control in the area of production/manufacturing



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### Technical data

Test bench/device	
<ul style="list-style-type: none"> <li>Basic mechanical design with test specimen holder for up to seven test specimens</li> <li>Test specimen holders for different test specimen types can be quickly changed</li> <li>Mechanical actuation of the test specimens via servo control climatic exposure test cabinet</li> <li>Measuring and testing technology in separate 19" rack</li> <li>Protective housing for connection to the climatic cabinet</li> </ul>	
Software	
<ul style="list-style-type: none"> <li>Multiprűf MP-WIN under Windows                             <ul style="list-style-type: none"> <li>- process control</li> <li>- measured value recording</li> <li>- measured value evaluation</li> <li>- Characteristic recording of the test specimens within the temperature ranges</li> <li>- extensive evaluation and statistics options</li> </ul> </li> <li>Menu-driven and configurable endurance test runs and climate cycles</li> </ul>	
Scope of testing	
<ul style="list-style-type: none"> <li>Measurement of switch-on times and switch-on/switch-off thresholds</li> <li>Continuous on-line monitoring of all sensors during dynamic movement</li> <li>Endurance test procedures, climate cycle</li> <li>Movement cycle independent of measuring cycle possible, fast movements e.g. 0° to 20° with 5 Hz</li> <li>75 measurement channels, differential,                             <ul style="list-style-type: none"> <li>- 2 measuring ranges 0...3 V/0 to 30 V, resolution 16 bit = 0.1 mV/1 mV, f = 1 kHz</li> </ul> </li> <li>16 measuring channels, differential, resolution 16 bit (1 mV), fsum = 500 kHz</li> </ul>	
Input-/visualisation units	Dimensions/Transport
<ul style="list-style-type: none"> <li>Keyboard</li> <li>Monitor</li> </ul>	<ul style="list-style-type: none"> <li>ca. 1200x800x600 mm (WxHxD)</li> </ul>
Test time	Exemplary device type
<ul style="list-style-type: none"> <li>Individual, depending on test scope</li> </ul>	<ul style="list-style-type: none"> <li>073 1420</li> </ul>